

## **AMENDMENTS TO THE CLAIMS**

The following listing of claims will replace all prior versions and listings of claims in the application:

### **WHAT IS CLAIMED IS:**

1. (Currently Amended) An integrated circuit comprising:  
a plurality of pins; and  
at least one respective scan path per pin.
2. (Original) The integrated circuit of claim 1 wherein:  
a first I/O pin is operable to input scan test data at a first test time; and  
the first I/O pin is operable to output scan test data at a second test time.
3. (Original) The integrated circuit of claim 2 wherein:  
the first I/O pin is operable to input scan test data to a first scan path at the first test time;  
a second I/O pin is operable to input scan test data to a second scan path at the first test time;  
the first I/O pin is operable to output scan test data from the second scan path at the second test time; and  
the second I/O pin is operable to output scan test data from the first scan path at the second test time.
4. (Original) The integrated circuit of claim 3 wherein the first scan path further comprises a series of scan paths.
5. (Original) The integrated circuit of claim 2 further comprising a series of scan paths wherein:  
the first I/O pin is operable to input scan test data to the series at a first test time; and

the first I/O pin is operable to output scan test data from the series at a second test time.

6. (Currently Amended) The integrated circuit of claim 2 further comprising functional circuitry wherein:

the scan path interacts with the functional circuitry; and  
the first I/O pin is operable to input scan test data at the first test time; and  
the first I/O pin is operable to output scan test data at the second test time.

7. (Currently Amended) The integrated circuit of claim 2 further comprising functional circuitry wherein:

the first I/O pin is operable to input functional test data at the first test time;  
and  
the first I/O pin is operable to output functional test data at a-the second test time.

8. (Currently Amended) An integrated circuit comprising:

a first I/O pin operable to receive input data during a test time; and  
a second I/O pin operable to provide output data during the test time,  
each I/O pin coupled to at least one respective scan path.

9. (Original) The integrated circuit of claim 8 further comprising a first scan path wherein:

the first I/O pin is operable to input scan test data during the test time; and  
the second I/O pin is operable to output scan test data during the test time.

10. (Original) The integrated circuit of claim 9 further comprising a second scan path wherein:

the first I/O pin is operable to input scan test data to the first scan path during the test time;

the output from the first scan path is input to the second scan path; and  
the second I/O pin is operable to output scan test from the second scan  
path data during the test time.

11. (Currently Amended) The integrated circuit of claim 9 further comprising  
any number of scan paths and the same number of I/O pins wherein:  
each I/O pin is operable to input scan test data during the test time;  
each I/O pin is operable to ~~input~~output scan test data during the test time;  
and  
a tester determines the function of each I/O pin during the test time.
12. (Currently Amended) An integrated circuit comprising;  
a functional circuit operable to produce functional output;  
~~a scan path operable to produce scan output;~~  
an I/O pin operable to be used as input at a first time and as output at a  
second time, the I/O pin having a respective scan path operable to  
produce scan output; and  
a flip-flop coupled to the I/O pin and to the functional circuit and to the  
scan path, the flip-flop operable to hold the functional output or the  
scan output for a clock cycle.
13. (Original) The integrated circuit of claim 12 further comprising:  
a number of scan paths;  
the same number of I/O pads; and  
the same number of flip-flops operable to form at least one register.
14. (Original) The integrated circuit of claim 13 wherein  
each I/O pad further comprises a scan output buffer;  
each flip-flop further comprises;  
a compact-control signal;  
an output-data signal; and

an and-gate operable to eliminate don't-care data; and  
the register is operable as a compaction register.

15. (Original) The integrated circuit of claim 13 wherein:  
each I/O pad further comprises;  
a reseed multiplexer operable to receive functional output data and scan  
input data;  
a reseed control signal operable to control the reseed multiplexer; and  
the register is operable as a reseed register.
16. (Currently Amended) The integrated circuit of claim 15 wherein:  
each I/O pad further comprises an ~~or~~XOR-gate operable to receive input  
from the output of a linear feedback shift register; and  
the register is operable as a linear feedback shift register.
17. (Original) The integrated circuit of claim 13 further comprising a second  
number of flip-flops operable to form a compaction register wherein:  
the integrated circuit is operable to perform reseeding; and  
the integrated circuit is at the same time operable to perform compaction.
18. (Original) The integrated circuit of claim 17 wherein the compaction  
register can be read serially.
19. (Currently Amended) A method comprising:  
inputting scan data to an I/O pin during a first time;  
processing the scan data in a respective scan path to produce scan output  
data; and  
outputting the scan output data to the I/O pin at a second time.
20. (Original) The method of claim 19 further comprising:  
multiplexing output data and scan output data; and

storing the output data or scan output data in a flip-flop during the first time.

21. (Original) The method of claim 20 further comprising:  
connecting a number of flip-flops associated with I/O pins; and  
forming a register performing a reseed test.
22. (Original) The method of claim 21 wherein forming a register further comprises:  
sending a compact control signal;  
and-gating the compact control signal with the output data;  
eliminating don't care data; and  
performing compaction.
23. (Original) The method of claim 21 wherein forming a register further comprises:  
sending a reseed control signal to a reseed multiplexer;  
multiplexing functional output data and scan input data; and  
performing a reseed test.
24. (Original) The method of claim 23 wherein multiplexing further comprises:  
receiving gated input from a linear feedback shift register; and  
performing a linear feedback shift register reseed test.
25. (Original) The method of claim 19 wherein the first time and the second time occur during the same clock cycle.